

JC20 Rec'd PET/PTO 18 OCT 2005

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 125664		APPLICATION NO. New U.S. National Stage of PCT/JP04/006003  <div style="font-size: 1.5em; font-weight: bold;">10/553754</div>	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT Makoto IIDA		FILING DATE October 18, 2005	

  

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

  

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
Smm	1	JP A 2002-201093 w/abstr. & trans.	07/16/2002	JAPAN		
Smm	2	JP A 2000-001391 w/abstr. & trans.	01/07/2000	JAPAN		
Smm	3	JP A 09-263485 w/abstr. & trans.	10/07/1997	JAPAN		
Smm	4	JP A 11-147786 w/abstr. & trans.	06/02/1999	JAPAN		
Smm	5	JP A 2000-044388 w/abstr. & trans.	02/15/2000	JAPAN		
Smm	6	JP A 11-349394 w/abstr. & trans.	12/21/1999	JAPAN		
Smm	7	JP A 2002-057160 w/abstr. & trans.	02/22/2002	JAPAN		

  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
Smm	8 V.V. VORONOKOV; "The Mechanism of Swirl Defects Formation in Silicon"; Journal of Crystal Growth; Vol. 59; March 1982; pp. 625-643

  

EXAMINER <div style="font-family: cursive; font-size: 1.2em;">D.M. Malik</div>	DATE CONSIDERED <div style="font-family: cursive; font-size: 1.2em;">03/14/2007</div>
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Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: October 18, 2005